GSMDC3908Z

30V N-Channel MOSFETs

Product Description

These N-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

These devices are well suited for high efficiency fast switching applications.

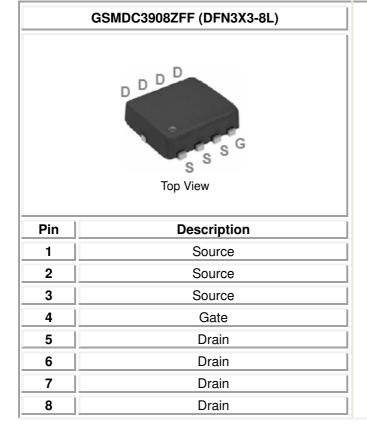
Features

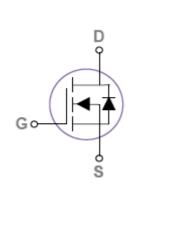
- 30V, 48A, $R_{DS(ON)}=7.8m\Omega@V_{GS}=10V$
- Improved dv/dt capability
- Fast switching
- 100% EAS guaranteed
- Green Device Available
- DFN3X3-8L package design

Applications

- MB / VGA / Vcore
- POL Applications
- SMPS 2nd SR

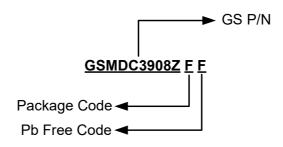
Packages & Pin Assignments





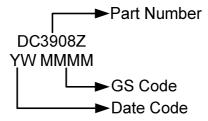


Ordering Information



Part Number	Package	Quantity
GSMDC3908ZFF	DFN3X3-8L	5000PCS

Marking Information



Absolute Maximum Ratings T_C=25°C Unless otherwise noted

Symbol	Parameter		Typical	Unit
V_{DS}	Drain-Source Voltage		30	V
V _{GS}	Gate –Source Voltage		±20	V
.	Continuous Drain Current	Tc=25°C	48	A
lσ		Tc=100°C	30	
I _{DM}	Pulsed Drain Current ¹		192	Α
EAS	Single Pulse Avalanche Energy ²		45	mJ
IAS	Single Pulse Avalanche Current ²		30	A
	Power Dissipation ($T_C=25^{\circ}C$)		35	W
P _D	Power Dissipation (Derate above 25°C)		0.28	W /℃
TJ	Operating Junction Temperature Range		-55 to +150	$^{\circ}\mathbb{C}$
T _{STG}	Storage Temperature Range		-55 to +150	${\mathbb C}$
$R_{\theta JA}$	Thermal Resistance-Junction to Ambient		62	°C/W
$R_{ heta JC}$	Thermal Resistance-Junction to Case		3.6	°C/W



Electrical Characteristics

T_J=25°C Unless otherwise noted

Symbol	Parameter	Conditions	Min	Тур	Max	Uni	
		Static					
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	V _{GS} =0V,I _D =250uA	30			V	
∆BV _{DSS} /∆T _J	BV _{DSS} Temperature Coefficient	Reference to 25°ℂ, I _D =1mA		0.04		V/°C	
$V_{\text{GS(th)}}$	Gate Threshold Voltage		1.2	1.6	2.5	V	
$\triangle V_{\text{GS(th)}}$	V _{GS(th)} Temperature Coefficient	V _{DS} =V _{GS} ,I _D =250uA		-4		mV ℃	
I _{GSS}	Gate-Source Leakage Current	V _{DS} =0V,V _{GS} =±20V			±100	nA	
		V _{DS} =30V,V _{GS} =0V			1	uA	
I _{DSS}	Drain-Source Leakage Current	V _{DS} =24V,V _{GS} =0V, T _J =125°C			10		
Is	Continuous Source Current	V _G =V _D =0V,			48	A	
Ism	Pulsed Source Current	Force Current			192		
R _{DS(on)}	Drain-Source On-Resistance	V _{GS} =10V,I _D =16A		6.5	7.8	i	
		V _{GS} =4.5V,I _D =8A		9.2	12	mΩ	
g FS	Forward Transconductance	V _{DS} =10V,I _D =8A		9.5		S	
$V_{ extsf{SD}}$	Diode Forward Voltage	V _{GS} =0V,I _S =1A			1	V	
EAS	Single Pulse Avalanche Energy	V _{DD} =25V,L=0.1mH, IAS=15A	V _{DD} =25V,L=0.1mH,			m	
t _{rr}	Reverse Recovery Time	Vgs=0V,ls=1A,		8.1		ns	
Q _{rr}	Reverse Recovery Charge	di/dt=100A/μs, T _J =25°C		1.6		nC	
		Dynamic					
Q_g	Total Gate Charge ^{3,4}			7.5	12		
Q_{gs}	Gate-Source Charge ^{3,4}	V _{DS} =15V,V _{GS} =4.5V, I _D =20A		1.3	2.6	nC	
Q_{gd}	Gate-Drain Charge ^{3,4}	10-2071		4.5	8		
Ciss	Input Capacitance			850	1700		
Coss	Output Capacitance	V _{DS} =25V,V _{GS} =0V, f=1MHz		133	260	pF	
Crss	Reverse Transfer Capacitance	1-1101112		78	160		
t _{d(on)}				4.8	9	ns	
tr	Turn-On Time ^{3,4}	V _{DD} =15V,I _D =15A,		12.5	24		
t _{d(off)}	Turn-Off Time ^{3,4}	$V_{GS}=10V,R_{G}=3.3\Omega$		27.6	52		
t f	Turn-Oil Time ^{s,-}			8.2	16		
R_g	Gate Resistance	V _{GS} =0V,V _{DS} =0V, f=1MHz		2.7	5.4	Ω	

Note

- ${\bf 1.}\ Repetitive\ Rating: Pulsed\ width\ limited\ by\ maximum\ junction\ temperature.$
- 2. V_{DD} =25V, V_{GS} =10V,L=0.1mH,IAS=30A., R_{G} =25 Ω ,Starting T_{J} =25 $^{\circ}$ C.
- 3. The data tested by pulsed , pulse width \leq 300us , duty cycle \leq 2%.
- 4. Essentially independent of operating temperature.



Typical Performance Characteristics

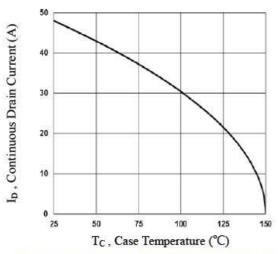


Fig.1 Continuous Drain Current vs. Tc

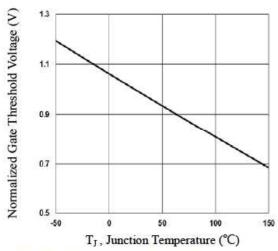


Fig.3 Normalized V_{th} vs. T_J

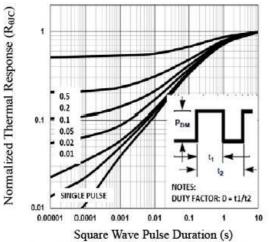


Fig.5 Normalized Transient Impedance

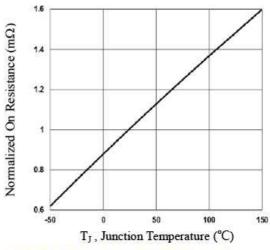


Fig.2 Normalized RDSON vs. T,

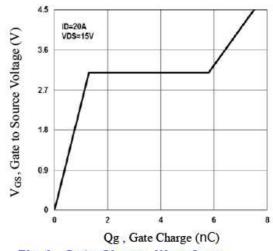


Fig.4 Gate Charge Waveform

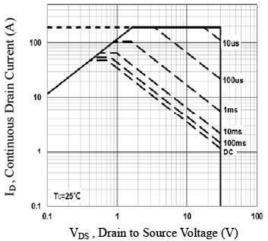
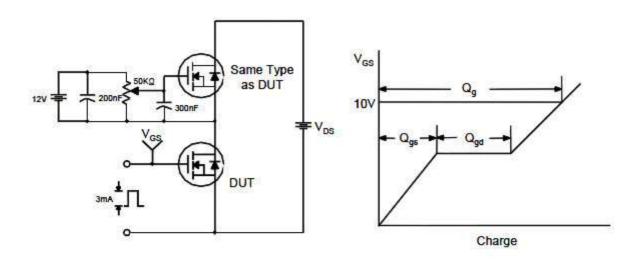


Fig.6 Maximum Safe Operation Area

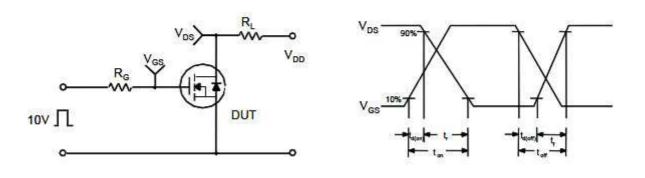


Typical Performance Characteristics (Continue)

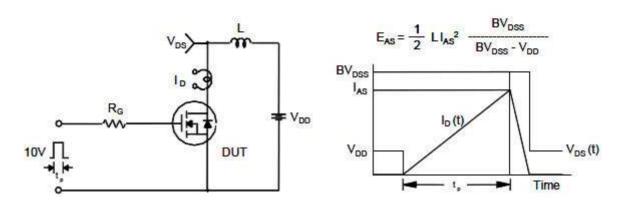
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms

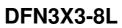


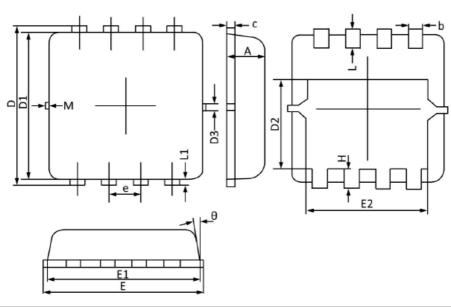
Unclamped Inductive Switching Test Circuit & Waveforms





Package Dimension





	Dimensions				
Cymphol	Millin	neters	Inches		
Symbol	Min	Max	Min	Max	
Α	0.700	0.800	0.028	0.031	
b	0.250	0.350	0.010	0.013	
С	0.100	0.250	0.004	0.009	
D	3.250	3.450	0.128	0.135	
D1	3.000	3.200	0.119	0.125	
D2	1.780	1.980	0.070	0.077	
D3	0.130 (REF)		0.005 (REF)		
E	3.200	3.400	0.126	0.133	
E1	3.000	3.200	0.119	0.125	
E2	2.390	2.590	0.094	0.102	
е	0.650	(BSC)	0.026 (BSC)		
Н	0.300	0.500	0.011	0.019	
L	0.300	0.500	0.011	0.019	
L1	0.130 (REF)		0.005 (REF)		
θ	0 °	12 °	0 °	12°	
М	0.150	(REF)	0.006	(REF)	



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